

AFM and SEM investigations of ion beam synthesized Mg₂Si precipitates in Si substrates

Angelov, Christo; **Mikli, Valdek**; Amov, Blagoj; Goranova, E. Journal of optoelectronics and advanced materials 2005 / 1, p. 369-373
https://old.joam.inoe.ro/arhiva/pdf7_1/Angelov3.pdf

Raman scattering characterization of ion-beam synthesized Mg₂Si. 1, Influence of the technological conditions on the formation of the Mg₂Si in(100) Si matrix

Atanassov, Alexander; Zlateva, Genoveva; Baleva, Mitra; Goranova, Ekaterina; Amov, Blagoj; Angelov, Christo; **Mikli, Valdek** Plasma processes and polymers 2006 / 2, p. 219-223 : ill <https://onlinelibrary.wiley.com/doi/pdf/10.1002/ppap.200500088>

Solid phase and ion beam epitaxial crystallization of Si implanted with Zn and Pb ions

Angelov, Christo; Georgiev, S.; Amov, Blagoj; **Mikli, Valdek**; Lohner, Tivador Journal of optoelectronics and advanced materials 2007 / 2, p. 311-314
https://www.researchgate.net/publication/289467840_Solid_phase_and_ion_beam_epitaxial_crystallization_of_Si_implanted_with_Zn_and_Pb_ions

Structural investigations of ion beam synthesized [beeta]-FeSi₂

Angelov, Christo; Amov, Blagoj; **Mikli, Valdek**; Traksmaa, Rainer Journal of optoelectronics and advanced materials 2009 / 10, p. 1490-1493 https://www.researchgate.net/publication/286966891_Structural_investigations_of_ion_beam_synthesized_b-FeSi2

Study of ion implanted Fe depth distribution in Si after pulsed ion beam treatment

Angelov, Christo; Georgiev, S.; Amov, Blagoj; Goranova, E.; **Mikli, Valdek**; Dezsi, I.; Kotai, E. Journal of optoelectronics and advanced materials 2007 / 2, p. 307-310
https://www.researchgate.net/publication/289186791_Study_of_the_ion_implanted_Fe_depth_distribution_in_Si_after_pulsed_ion_beam_treatment